Notice of References Cited Application/Control No. 10/538,435 Examiner KEVIN S. MAI Applicant(s)/Patent Under Reexamination VAU ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0032905	03-2002	Sherr et al.	725/38
*	В	US-2001/0056578	12-2001	Hwang et al.	725/98
*	С	US-2002/0071139	06-2002	Janik, Craig M.	358/1.15
*	D	US-2004/0174327	09-2004	Bowden et al.	345/084
*	Е	US-2003/0011682	01-2003	Sellen et al.	348/207.1
*	F	US-2002/0152193	10-2002	Thompson et al.	707/1
*	G	US-2002/0126150	09-2002	Parry, Travis J.	345/771
*	Н	US-6,975,308	12-2005	Bitetto et al.	345/204
*	I	US-2004/0111749	06-2004	Zhang et al.	725/087
*	J	US-2004/0003151	01-2004	Bateman et al.	710/72
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C					
	V					
	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.